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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.	
10/781,693	02/20/2004	Shigeo Kiso	03500.018040	3687	
5514	7590 04/18	006	EXAM	EXAMINER	
FITZPATRICK CELLA HARPER & SCINTO 30 ROCKEFELLER PLAZA NEW YORK, NY 10112			LE, UYEN	I CHAU N	
			ART UNIT	PAPER NUMBER	
			2876	2876	

DATE MAILED: 04/18/2006

Please find below and/or attached an Office communication concerning this application or proceeding.

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	Application No.	Applicant(s)				
Office Action Comment	10/781,693	KISO, SHIGEO				
Office Action Summary	Examiner	Art Unit				
	Uyen-Chau N. Le	2876				
The MAILING DATE of this communication appeared for Reply	ppears on the cover sheet with	the correspondence address				
A SHORTENED STATUTORY PERIOD FOR REP WHICHEVER IS LONGER, FROM THE MAILING  - Extensions of time may be available under the provisions of 37 CFR 1 after SIX (6) MONTHS from the mailing date of this communication.  - If NO period for reply is specified above, the maximum statutory perio  - Failure to reply within the set or extended period for reply will, by statu Any reply received by the Office later than three months after the mail earned patent term adjustment. See 37 CFR 1.704(b).	DATE OF THIS COMMUNICA  1.136(a). In no event, however, may a reply d will apply and will expire SIX (6) MONTH: the, cause the application to become ABAN	TION. y be timely filed S from the mailing date of this communication. DONED (35 U.S.C. § 133).				
Status						
1) Responsive to communication(s) filed on 20	January 2006.					
3) Since this application is in condition for allow	3) Since this application is in condition for allowance except for formal matters, prosecution as to the merits is					
closed in accordance with the practice under	Ex parte Quayle, 1935 C.D. 1	1, 453 O.G. 213.				
Disposition of Claims						
4)⊠ Claim(s) 1,2 and 4-18 is/are pending in the a	pplication.					
	4a) Of the above claim(s) is/are withdrawn from consideration.					
5) Claim(s) is/are allowed.						
6) Claim(s) <u>1,2 and 4-18</u> is/are rejected.						
7) Claim(s) is/are objected to.						
8) Claim(s) are subject to restriction and	or election requirement.					
Application Papers						
9) The specification is objected to by the Examir	ner.					
10)☐ The drawing(s) filed on is/are: a)☐ ac	ccepted or b) objected to by	the Examiner.				
Applicant may not request that any objection to th	e drawing(s) be held in abeyance	. See 37 CFR 1.85(a).				
Replacement drawing sheet(s) including the corre		•				
11)☐ The oath or declaration is objected to by the I	Examiner. Note the attached C	Office Action or form PTO-152.				
Priority under 35 U.S.C. § 119						
12)⊠ Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f). a)⊠ All b)□ Some * c)□ None of:						
1.⊠ Certified copies of the priority documents have been received.						
2. Certified copies of the priority documents have been received in Application No						
<ol><li>Copies of the certified copies of the pri</li></ol>	3. Copies of the certified copies of the priority documents have been received in this National Stage					
application from the International Bure	* **					
* See the attached detailed Office action for a lis	st of the certified copies not rec	ceived.				
Attachment(s)						
1) X Notice of References Cited (PTO-892)	4) 🔲 Interview Sum	nmary (PTO-413)				
2) D Notice of Draftsperson's Patent Drawing Review (PTO-948)	Paper No(s)/N	Mail Date mal Patent Application (PTO-152)				
<ol> <li>Information Disclosure Statement(s) (PTO-1449 or PTO/SB/08 Paper No(s)/Mail Date <u>02/06/2006</u>.</li> </ol>	6) Other:	mai r atent Application (PTO-192)				

#### DETAILED ACTION

## Prelim. Amdt/Amendment

1. Receipt is acknowledged of the Amendment filed 20 January 2006.

#### Claim Rejections - 35 USC § 102

2. The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless -

- (b) the invention was patented or described in a printed publication in this or a foreign country or in public use or on sale in this country, more than one year prior to the date of application for patent in the United States.
- 3. Claims 1, 2, 4-8, 13-14 and 15-17 are rejected under 35 U.S.C. 102(b) as being anticipated by Hashimoto (JP 02134747 A).

Re claims 1, 2, 4-8, 13-14 and 15-17: Hashimoto discloses a method of producing a substrate with mark, comprising: a marking step of forming a mark having an information on a surface of a substrate; and a reading step of reading the mark, wherein prior to the reading step, at least a part of the mark is formed in a region of the substrate where a factor that hinders the reading of the mark in the reading step is not generated; wherein in the marking step, the mark is formed in a direction nonparallel

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(i.e., orthogonal) to the direction of generation of the factor that hinders reading of the mark; wherein the marking step, the mark formed in plurality such that the marking positions of at least two consecutive ones of the marks are offset with respect to each other in a direction perpendicular (i.e., orthogonal) to the direction of generation of the factor that hinders reading of the marks; wherein the factor that hinders reading of the mark is deformation of the substrate; wherein the factor that hinders reading the mark is film attachment to the substrate; wherein the factor that hinders reading of the mark is a change in color of the substrate; wherein the factor that hinders reading of the mark is coloring of the substrate (i.e., the pattern is formed and is colored black); wherein the marking step, the mark formed while moving the substrate (i.e., while the card 19 is transported); wherein the substrate 19 is a nonlight transmissive substrate and is a photovoltaic element

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#### Claim Rejections - 35 USC § 103

substrate; wherein the mark comprises a character, a bar

code(i.e., pattern) (see English abstract).

4. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

- (a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.
- 5. Claims 1, 6-8, 10-12, 15 and 18 are rejected under 35 U.S.C. 103(a) as being unpatentable over Nishida et al (US 5,272,322) in view of van den Brink et al (US 4778275 A).

Re claims 1, 6-8, 10-12, 15 and 18: Nishida et al discloses a method of producing a substrate with mark, comprising: a marking step of forming a mark having an information on a surface of a substrate; and a reading step of reading the mark, wherein prior to the reading step, at least a part of the mark is formed in a region of the substrate where a factor that hinders the reading of the mark in the reading step is not generated; wherein the factor that hinders reading of the mark is a change in color of the substrate; wherein the factor that hinders reading of the mark is coloring of the substrate; wherein the marking step, the mark formed while moving the substrate; wherein the substrate a continuous member, which is a roll-to-roll system; wherein of the mark comprises character, a bar code la, wherein the mark is formed by printing (figs. 4-10; col. 5, line 30 through col. 9, line 22).

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Nishida et al is silent with respect to the plurality of marks is formed such that the marking positions of at least two consecutive ones of the plurality of marks are offset with respect to each other in a direction perpendicular to the direction of generation of the factor that hinders reading of the plurality of marks.

van den Brink et al teaches the plurality of marks  $M_2$  is formed such that the marking positions of the plurality of marks are offset with respect to one another in a direction perpendicular to the direction of generation of the factor that hinders reading of the plurality of marks (col. 4, lines 21-31 and col. 12, lines 10-44).

It would have been obvious to an artisan of ordinary skill in the art at the time the invention was made to incorporate the teachings of van den Brink et al into the system as taught by Nishida et al in order to provide Nishida et al with a more accurate system for detecting and correcting deformations or irregularities in the substrate during alignment/moving process.

6. Claim 9 is rejected under 35 U.S.C. 103(a) as being unpatentable over Nishida et al as modified by van den Brink et al as applied to claim 1 above, and further in view of Liu et al (US 5,777,310). The teachings of Nishida et al as modified by van den Brink et al have been discussed above.

Re claim 9: Nishida et al/van den Brink et al has been discussed above, but is silent with respect to a portion of the mark subjected to hindrance to reading due to the factor that hinders reading of the mark is inferred and implemented based on the results of reading of ones of the marks formed preceding and succeeding the formation of the mark subjected to the hindrance to reading.

Liu et al teaches a portion of the mark subjected to hindrance to reading due to the factor that hinders reading of the mark is inferred and implemented based on the results of reading of ones of the marks formed preceding and succeeding the formation of the mark subjected to the hindrance to reading (figs. 1 and 4a-4e; col. 5, lines 22-36).

It would have been obvious to an artisan of ordinary skill in the art at the time the invention was made to incorporate the teachings of Liu et al into the system as taught by Nishida et al/van den Brink et al in order to provide Nishida et al/van den Brink et al with the ability of successfully and accurately reading codes with factors that hinders the reading process (e.g., damaged codes), wherein incorrect printed codes can be corrected/determined readily upon detection, thus providing a more efficient system.

### Response to Arguments

- 7. Applicant's arguments filed 01/20/2006 have been fully considered but they are not persuasive.
- 8. In response to applicant's argument that the references fail to show certain features of applicant's invention, it is noted that the features upon which applicant relies (i.e., the data is made up of marks which are offset with respect to each other in a direction perpendicular to the direction of generation of the deformation) are not recited in the rejected claim(s). Although the claims are interpreted in light of the specification, limitations from the specification are not read into the claims. See In re Van Geuns, 988 F.2d 1181, 26 USPQ2d 1057 (Fed. Cir. 1993).

#### Conclusion

9. Applicant's amendment necessitated the new ground(s) of rejection presented in this Office action. Accordingly, THIS ACTION IS MADE FINAL. See MPEP § 706.07(a). Applicant is reminded of the extension of time policy as set forth in 37 CFR 1.136(a).

A shortened statutory period for reply to this final action is set to expire THREE MONTHS from the mailing date of this action. In the event a first reply is filed within TWO MONTHS.

of the mailing date of this final action and the advisory action is not mailed until after the end of the THREE-MONTH shortened statutory period, then the shortened statutory period will expire on the date the advisory action is mailed, and any extension fee pursuant to 37 CFR 1.136(a) will be calculated from the mailing date of the advisory action. In no event, however, will the statutory period for reply expire later than SIX MONTHS from the date of this final action.

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Uyen-Chau N. Le whose telephone number is 571-272-2397. The examiner can normally be reached on First Monday 5:30AM-1:30PM and Tues-Fri 5:30AM-3PM.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Michael G. Lee can be reached on 571-272-2398. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

Uyen-Chau N. Le Primary Examiner Art Unit 2876

Uchaule

April 7, 2006